

Search Notes

Application/Control No.

10/644,362

Examiner

Hai L. Nguyen

Applicant(s)/Patent under
Reexamination

PAIST ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	113-119, 141,162, 146-148, 163	3/4/2005	HLN
	154-157		
331	DIG.2		
375	373-376		
455	260		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Search	Above	3/5/2005	HLN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	3/5/2005	HLN